ABSTRACT OF THE DISCLOSURE

There is provided a power transistor, as well as semiconductor integrated circuit using the power transistor, in which malfunctions of parasitic transistor and circuit malfunctions due to latch-up of peripheral circuits can be prevented. In a power transistor composed of a plurality of vertical transistors arrayed on a P-type silicon substrate, singularity or plurality of electrode portions of an $N^{\scriptscriptstyle\mathsf{t}}$ type buried layer formed to isolate the P-type silicon substrate and collectors of the plurality of vertical PNP transistors from each other are provided in an active region of the power transistor.

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